


<b>Search Notes</b>  	<b>Application/Control No.</b>  10044420	<b>Applicant(s)/Patent Under Reexamination</b>  BERKNER ET AL.
	<b>Examiner</b>  Hung, Yubin	<b>Art Unit</b>  2624

SEARCHED			
Class	Subclass	Date	Examiner
382	166,173,232,233,235,248	3/26/07	YH
348	403.1	3/26/07	YH
375	240.18,240.19	3/26/07	YH
708	203	3/26/07	YH

SEARCH NOTES			
Search Notes		Date	Examiner
EAST Text search (USPGPUB, USPAT, EPO, JPO, DERWENT, IBM-TDB)		3/26/07	YH
ACM		7/27/05	YH
SPIE		7/28/05	YH
IEEE Xplore		12/9/05	YH
Consulted with Wenpeng Chen (Claim 92)		7/26/05	YH

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
382	235,173	3/26/07	YH